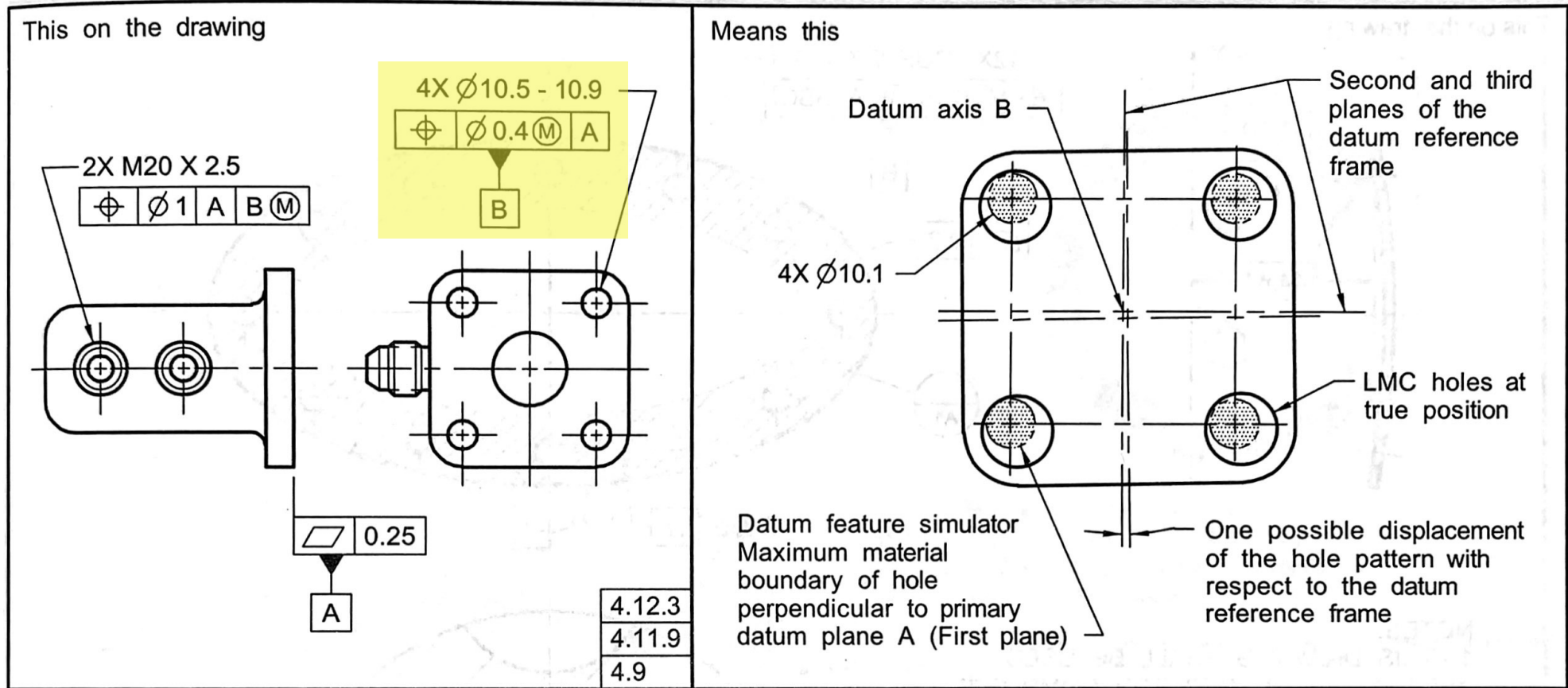


Fig. 4-26 Hole Pattern Identified as Datum



4.12.3 Pattern of Features of Size at MMB

Multiple features of size, such as a pattern of holes at MMB, may be used as a group in the establishment of a datum feature simulator to derive a datum reference frame. See Fig. 4-26. In this case, when the part is mounted on the datum feature simulator of primary datum feature A, the pattern of holes establishes the datum feature simulator that is used to derive the second and third planes of the datum reference frame. The datum feature simulator of datum feature B is the collection of the MMB of all of the holes located at true position. The origin of the datum reference frame may be established at the **center of the pattern** of the datum feature simulator where it intersects plane A, as shown in Fig. 4-26 or at any other location defined with basic dimensions relative to the datum feature simulator as in Fig. 4-28. Where datum feature B is referenced at MMB, a displacement is permitted between the actual hole pattern and the datum reference frame. Such displacement is related to any clearance between the surface of datum feature B and the MMB of each hole. This clearance is determined by the size, orientation, and location of each of the holes collectively.

4.12.4 Pattern of Features of Size at RMB

Where RMB is applied in a feature control frame to multiple datum features of size used to establish a single datum, the datum feature simulator of each feature shall be fixed in a location relative to one another. The datum feature simulators shall expand or contract simultaneously from their MMB to their LMB until the datum feature simulators make maximum possible contact with the extremities of the datum feature(s). See Fig. 4-25.